10/614,997

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1	("6574760").PN.	US-PGPUB; USPAT	OR	OFF	2007/10/14 20:38
S3	1	executing second test same (concurrently or simultanously) same (processing test data same first test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 20:49
S4	1	(program\$4 or prepar\$3) same (subsequent test\$1) same (concurrently) same (test executing near2 semiconductor device)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 20:45
S5	11	concurrently execut\$3 and ((second test or subsequent test\$1) same (process\$3 same first test))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:16
S6	1	prepar\$3 and ((execution near2 (second test\$1 or subsequent test\$1)) same (concurrently near2 executing near2 first test))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 20:52
S7	2	prepar\$3 and ((execut\$3 same (second test\$1 or subsequent test\$1)) and (concurrently same execut\$3 same first test))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 20:53
S8	1	S5 and S7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 20:53

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S9	1	software computation module\$1 concurrently executing near2 processor	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:15
S10		software computation module\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 23:56
S11	1	first and second tests same wafer testing same package testing same mixed signal semiconductor device	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/14 23:57
S12	. 1	(executing near1 first test) same (preparing execution near2 second test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:06
S13	33	execut\$3 and (test script\$1 same first test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:12
S14	2	identify\$3 and (hardware element\$1 same second test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:09
S15	1	configur\$3 and (hardware element\$1 same second test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:09

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S16	11	concurrently execut\$3 and ((second test or subsequent test\$1) same (process\$3 same first test))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:13
S17	1	S13 and S16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:13
S18	. 35	mixed signal semiconductor device	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:14
S19	1	S18 and S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:14
S20	16	mixed signal semiconductor device and (testing or device under test or unit under test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:15
S21	16	S18 and S20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:15
S22		S21 and S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:15

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523	79	device under test interface .	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:16
S28	. 14	concurrently execut\$3 and ((second test or subsequent test\$1) and (process\$3 same first test))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:28
S29	1	S18 and S28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:17
S30	1	S20 and S28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:17
S31	1	S10 and S28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:17
S32	1	S28 and S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:18
S33	3144	test instruction\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:19

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S34	2	S28 and S33	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:19
S35	52569	714/724 or 714/733 or 714/734 or 714/10 or 714/11 or 714/30 or 714/38 or 714/742 or 714/740 or 714/? or 702/118 or 702/? or 717/? or 707/? or 716/4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:33
S36	6	S35 and S28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:32
S37	. 14	S35 and S23	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:33
S38	1	S28 and S20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:33
S39	6	S28 and S35	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:35
S40	555	717/125	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:35

S41	1	S40 and S39	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:35
S42	1	S40 and S28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/10/15 00:35